Call for Contributions

Open Mobile Network Interface (OMNI) Standard for an IEEE 802 HetNet

HetNet Study Group

Issued: 19 May 2012 Deadline: 11 July 2012 AOE

On 16 March 2012, the IEEE 802 Executive Committee chartered the Study Group on the WirelessMAN Radio Interface in Heterogeneous Networks (HetNet Study Group), under the IEEE 802.16 Working Group, through 19 July 2012, with the possibility of extension until November 2012.

During the IEEE 802.16 Working Group's Session #79, of 14-17 May, the Study Group reviewed multiple input contributions, including a proposal to initiate and lead the development of a PAR on a new Open Mobile Network Interface (OMNI) as the basis of an IEEE 802 heterogeneous network. Input documents, along with Study Group output documents, are available at http://docii.wirelessman.org.

In advance of the Study Group's next meeting, during the IEEE 802.16 Working Group's Session #80 of 16-19 July, the Study Group is issuing this Call for Contributions requesting further views on the Open Mobile Network Interface (OMNI) and an IEEE 802 heterogeneous network specification. In particular, the Study Group seeks inputs on the following topics:

- (1) Comments on the OMNI proposal reviewed at Session #79.
- (2) Proposals regarding the architecture of the OMNI as it might be developed within IEEE 802.
- (3) Proposals regarding the specific functionality to be provided by the OMNI.
- (4) Proposals regarding the utility of the OMNI and comparisons to alternative network approaches.
- (5) Proposals regarding the organizational approach within IEEE 802 for the development of an OMNI standard with the appropriate engagement of the relevant current Working Groups.
- (6) Proposals toward the draft PAR and Five Criteria Statement.

Submit your contribution by the **deadline of 11 July 2012** following the IEEE 802.16 Document Submission Instructions http://ieee802.org/16/submit.html using the File Code "Shet".

For further information, contact the following:

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